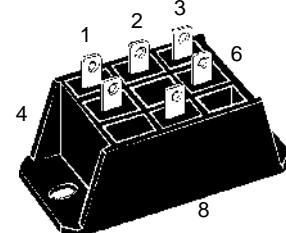
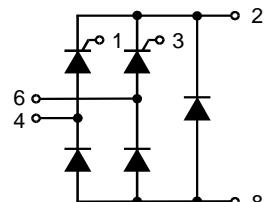


Half Controlled Single Phase Rectifier Bridge with Freewheeling Diode

I_{dAVM} = 21 A
V_{RRM} = 800-1600 V

V _{RSM} V _{DSM}	V _{RRM} V _{DRM}	Type
900	800	VHF 15-08io5
1300	1200	VHF 15-12io5
1500	1400	VHF 15-14io5
1700	1600	VHF 15-16io5



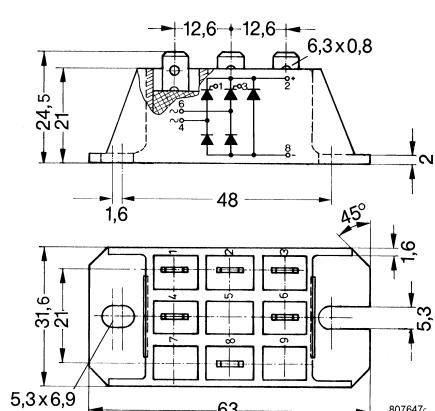
Symbol	Test Conditions	Maximum Ratings			Features
I _{dAV}	T _K = 85°C, module	15	A		• Package with DCB ceramic base plate
I _{dAVM} ①	module	21	A		• Isolation voltage 3600 V~
I _{FRMS} , I _{TRMS}	per leg	15	A		• Planar passivated chips
I _{FSM} , I _{TSM}	T _{VJ} = 45°C; V _R = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	190 210	A A	• 1/4" fast-on terminals
	T _{VJ} = T _{VJM} V _R = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	170 190	A A	• UL registered E 72873
I ² t	T _{VJ} = 45°C V _R = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	160 180	A ² s A ² s	
	T _{VJ} = T _{VJM} V _R = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	140 145	A ² s A ² s	
(di/dt) _{cr}	T _{VJ} = 125°C f = 50 Hz, t _p = 200 μs V _D = 2/3 V _{DRM} I _G = 0.3 A, di _G /dt = 0.3 A/μs	repetitive, I _T = 50 A non repetitive, I _T = 1/2 • I _{dAV}	150 500	A/μs A/μs	
(dv/dt) _{cr}	T _{VJ} = T _{VJM} ; V _{DR} = 2/3 V _{DRM} R _{gk} = ∞; method 1 (linear voltage rise)		1000	V/μs	
V _{RGM}			10	V	
P _{GM}	T _{VJ} = T _{VJM} I _T = I _{TAVM}	t _p = 30 μs t _p = 500 μs t _p = 10 ms	≤ 10 ≤ 5 ≤ 1 0.5	W W W W	
P _{GAVM}			-40...+125 125 -40...+125	°C °C °C	
T _{VJ}					
T _{VJM}					
T _{stg}					
V _{ISOL}	50/60 Hz, RMS I _{ISOL} ≤ 1 mA	t = 1 min t = 1 s	3000 3600	V~ V~	
M _d	Mounting torque (M5) (10-32 UNF)		2-2.5 18-22	Nm lb.in.	
Weight			50	g	

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.

① for resistive load

IXYS reserves the right to change limits, test conditions and dimensions.

Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
I_R, I_D	$V_R = V_{RRM}; V_D = V_{DRM}$ $T_{VJ} = T_{VJM}$ $T_{VJ} = 25^\circ C$	≤ 5	mA	
		≤ 0.3	mA	
V_T, V_F	$I_T, I_F = 45 A; T_{VJ} = 25^\circ C$	≤ 2.8	V	
V_{TO}	For power-loss calculations only ($T_{VJ} = 125^\circ C$)	1.0	V	
r_T		40	$m\Omega$	
V_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$	≤ 1.0	V	
		≤ 1.2	V	
I_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤ 65	mA	
		≤ 80	mA	
		≤ 50	mA	
V_{GD}	$T_{VJ} = T_{VJM};$ $T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤ 0.2	V
I_{GD}		$V_D = 2/3 V_{DRM}$	≤ 5	mA
I_L	$I_G = 0.3 A; t_G = 30 \mu s;$ $di_G/dt = 0.3 A/\mu s;$ $T_{VJ} = 25^\circ C$	≤ 150	mA	
	$T_{VJ} = -40^\circ C$	≤ 200	mA	
	$T_{VJ} = 125^\circ C$	≤ 100	mA	
I_H	$T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$	≤ 100	mA	
t_{gd}	$T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$ $I_G = 0.3 A; di_G/dt = 0.3 A/\mu s$	≤ 2	μs	
t_q	$T_{VJ} = 125^\circ C, I_T = 15 A, t_p = 300 \mu s, V_R = 100 V$	typ.	150	μs
Q_r	$di/dt = -10 A/\mu s, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$		75	μC
R_{thJC}	per thyristor (diode); DC current	2.4	K/W	
	per module	0.6	K/W	
R_{thJK}	per thyristor (diode); DC current	3.0	K/W	
	per module	0.75	K/W	
d_s	Creepage distance on surface	12.6	mm	
d_a	Creepage distance in air	6.3	mm	
a	Max. allowable acceleration	50	m/s^2	

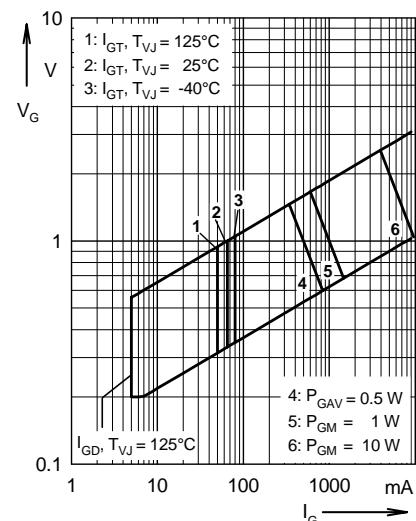
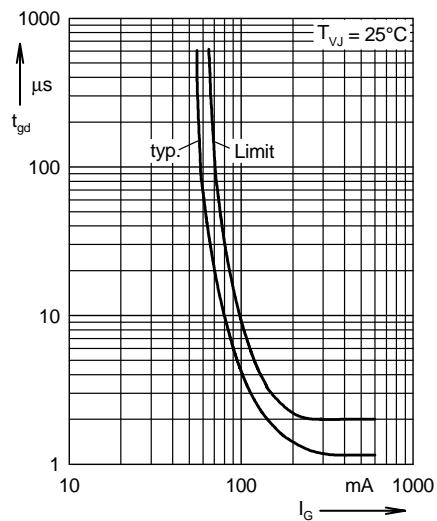


Fig. 1 Gate trigger range

Fig. 2 Gate controlled delay time t_{gd}

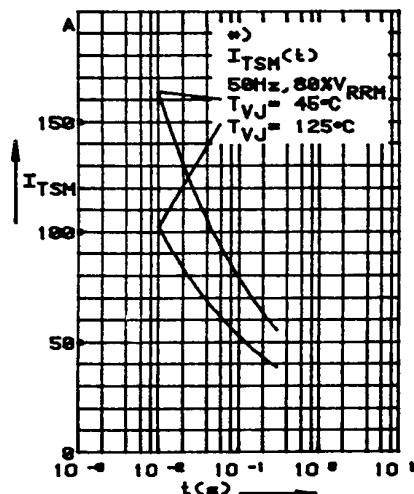


Fig. 3 Surge overload current per chip
 I_{TSM} : Crest value, t : duration

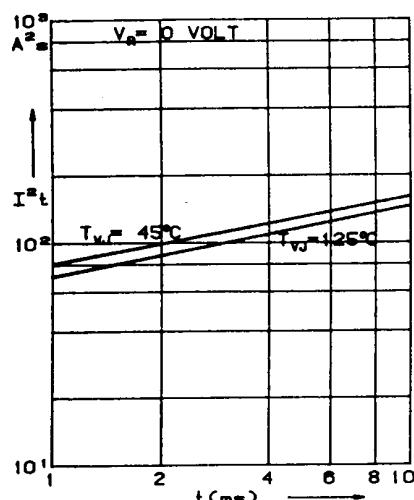


Fig. 4 I^2t versus time (1-10 ms)
per chip

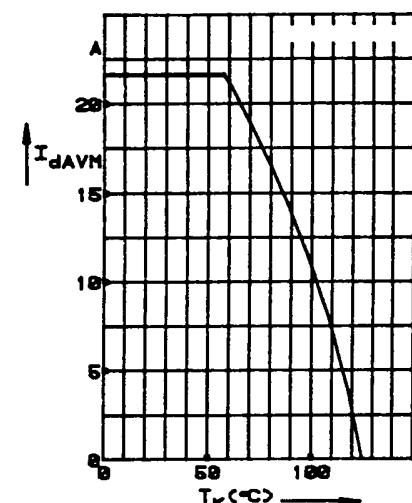


Fig. 5 Max. forward current at
heatsink temperature

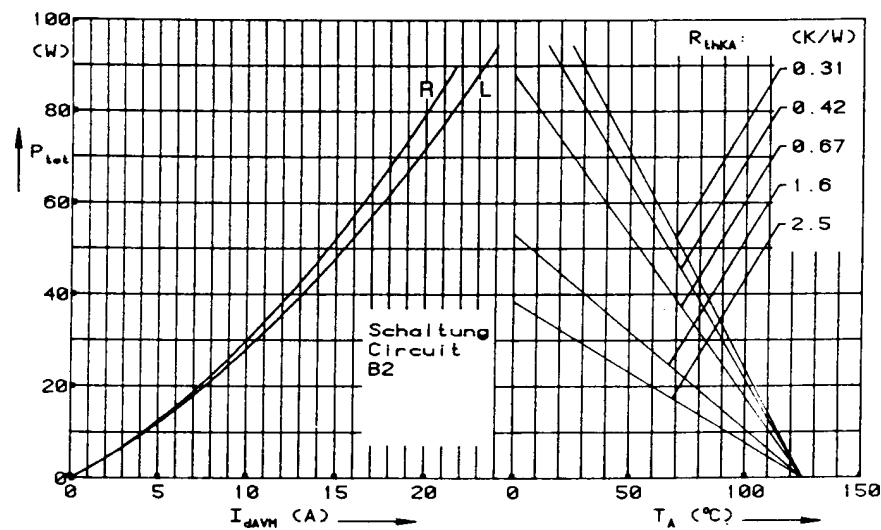


Fig. 6 Power dissipation versus direct output current and ambient temperature

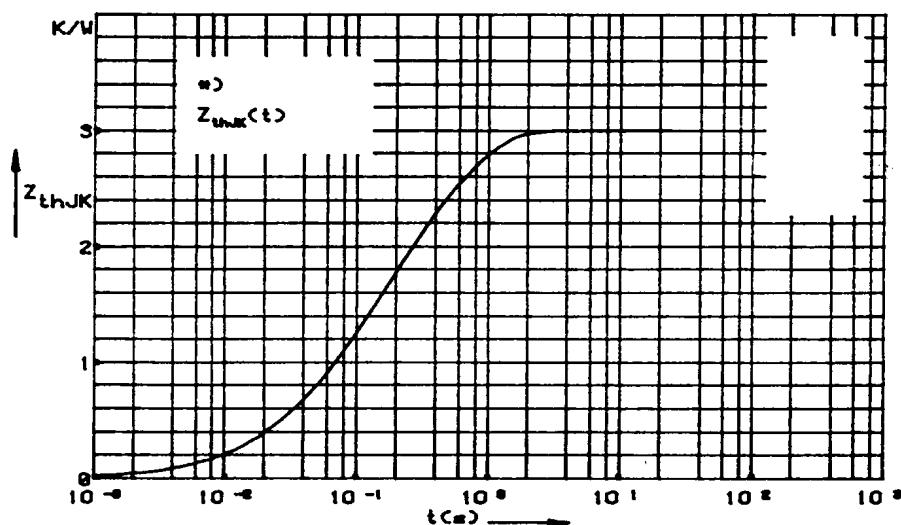


Fig. 7 Transient thermal impedance junction to heatsink per chip

Constants for Z_{thJK} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.34	0.0344
2	1.16	0.12
3	1.5	0.5